Determining Interplanar Distances from STEM-EDX Hyperspectral Maps.

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Since the first demonstration of atomically resolved energy dispersive x-ray spectroscopy (EDX) using a scanning transmission electron microscope (STEM) in 2010 [1], theory based simulations established that EDS hyperspectral maps could be used to measure atomic distances. That is, EDX is an incoherent imaging mode and signal intensity corresponds directly to the structure of the sample [1]. It has also been demonstrated that fractional occupancies of chemical species can be quantified [2]. Here we present results exhibiting statistically significant atomic species-dependent differences in interplanar distances in addition to quantification of planar occupancies. It has been observed that rock salt structured 2D layers exhibit systematic variability in structure associated with thickness [3,4] and adjacent constituents [5]. To observe these effects in the context of an alloy system, a series of layered (Pb_xSn_1-xSe)_1+δTiSe_2 films were self-assembled from designed precursors using a modulated elemental reactant (MER) method in a custom physical vapor deposition system [6]. These films consist of alternating bilayers of Pb_xSn_1-xSe and monolayers TiSe_2. Prior results indicated that the films form a solid solution through the bulk miscibility gap [7]. Present in the alloy samples are occasional formations of rock salt-like Pb_xSn_1-xSe hexalayers with segregation of Pb to the outermost layer. Consistent with prior observations of low-dimensional rock salt structures, our in-depth analysis of the heterostructured hexalayer and bilayer alloys finds systematic element specific interplanar distances of the different chemical species (Pb, Sn, and Se). These results are corroborated with refinement of (00l) x-ray diffraction patterns and density functional theory calculations. Additionally we corroborate the finding that EDX peak intensities from off zone axis (rotationally disordered) atomic planes can be used for quantification [8] as the quantified intensities from our calibrated Pb_xSn_1-xSe alloy series scale as expected. [9]

References:
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**Figure 1.** A schematic illustrating the extraction of EDX peak intensities from a hyperspectral data cube and the Gaussian peak fits and residuals for extracting element specific interplanar distances and intraplanar composition.